

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of: Byoung-Ho LEE, et al.

Serial No.: 10/754,013 Examiner: Newman, Michael A.

Filed: January 5, 2004 Group Art Unit: 2609

Confirmation No.: 7107

For: METHOD AND APPARATUS FOR DETECTING DEFECTS ON A  
WAFER

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT**

Responsive to the Office Action, Paper No. 20070523, dated June 1, 2007, please amend the application as follows.

- **Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.
- **Remarks/Arguments** begin on page 8 of this paper.